L Number	Hits	Search Text	DB	Time stamp
1	16	250/\$.ccls. and electron adj beam and lens and shield and conductive and	USPAT;	2003/04/23 08:18
		resistive	EPO; JPO;	
			DERWENT	
2	151	250/\$.ccls. and electron adj beam and objective adj lens and shield	USPAT;	2003/04/23 08:49
			EPO; JPO;	
			DERWENT	
3	102	250/\$.ccls. and electron adj beam and objective adj lens and electrostatic	USPAT;	2003/04/23 08:26
		adj deflector	EPO; JPO;	
			DERWENT	
4	23	250/\$.ccls. and electron adj beam and objective adj lens and electrostatic	USPAT;	2003/04/23 08:27
		adj deflector not magnetic	EPO; JPO;	
			DERWENT	
5	10	(250/\$.ccls. and electron adj beam and objective adj lens and electrostatic	USPAT;	2003/04/23 08:27
		adj deflector not magnetic) and secondary adj electron	EPO; JPO;	
			DERWENT	
12	20	250/\$.ccls. and electron adj beam and objective adj lens and deflector and	USPAT;	2003/04/23 10:48
		auger adj electron	EPO; JPO;	
			DERWENT	
25	6	250/\$.ccls. and electron adj beam and lens and deflector and auger adj	USPAT;	2003/04/23 10:41
		electron and capacitor	EPO; JPO;	
			DERWENT	
26	19	250/\$.ccls. and electron adj beam and objective adj lens and deflector and	USPAT;	2003/04/23 10:48
		auger adj electron and image	EPO; JPO;	
			DERWENT	